Application/Control No.	Applicant(s)/Patent Under Reexamination		
10537767	ENDO ET AL.		
Examiner	Art Unit		
Lee, Ph.D., Jae W	1656		
	10537767 Examiner		

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Claims	renumbered	in the same ord	ler as present	ed by applicant		☐ CPA	□ т	.D. 🗆	R.1.47
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